



**ALPHA & OMEGA**  
SEMICONDUCTOR



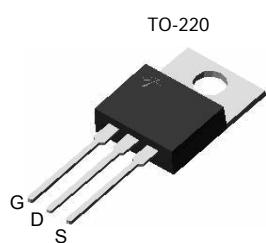
## AOT14N50 / AOTF14N50 500V, 14A N-Channel MOSFET

### General Description

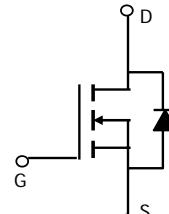
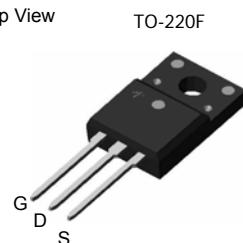
The AOT14N50 & AOTF14N50 have been fabricated using an advanced high voltage MOSFET process that is designed to deliver high levels of performance and robustness in popular AC-DC applications. By providing low  $R_{DS(on)}$ ,  $C_{iss}$  and  $C_{rss}$  along with guaranteed avalanche capability these parts can be adopted quickly into new and existing offline power supply designs.

### Features

$V_{DS}$  (V) = 600V@150°C  
 $I_D$ =14A  
 $R_{DS(ON)} < 0.38\Omega$  ( $V_{GS} = 10V$ )  
**100% UIS Tested!**  
**100%  $R_g$  Tested!**



Top View



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	AOT14N50	AOTF14N50	Units
Drain-Source Voltage	$V_{DS}$	500		V
Gate-Source Voltage	$V_{GS}$	$\pm 30$		V
Continuous Drain Current	$T_C=25^\circ C$ $T_C=100^\circ C$	$I_D$	14	A
Current			9.6	
Pulsed Drain Current	$I_{DM}$	56		
Avalanche Current <sup>C, G</sup>	$I_{AR}$	6		A
Repetitive avalanche energy <sup>C, G</sup>	$E_{AR}$	540		mJ
Single pulsed avalanche energy <sup>G</sup>	$E_{AS}$	1080		mJ
Peak diode recovery dv/dt	dv/dt	5		V/ns
Power Dissipation <sup>B</sup>	$T_C=25^\circ C$ Derate above $25^\circ C$	$P_D$	223	W
			1.8	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-50 to 150		°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	$T_L$	300		°C

### Thermal Characteristics

Parameter	Symbol	AOT14N50	AOTF14N50	Units
Maximum Junction-to-Ambient <sup>A,D</sup>	$R_{\theta JA}$	65	65	°C/W
Maximum Case-to-Sink <sup>A</sup>	$R_{\theta CS}$	0.5	--	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	0.56	2.5	°C/W

\* Drain current limited by maximum junction temperature.

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=25^\circ\text{C}$	500			V
		$I_D=250\mu\text{A}, V_{GS}=0\text{V}, T_J=150^\circ\text{C}$		600		V
$\text{BV}_{\text{DSS}}/\Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$		0.5		$\text{V}/^\circ\text{C}$
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=500\text{V}, V_{GS}=0\text{V}$		1		$\mu\text{A}$
		$V_{DS}=400\text{V}, T_J=125^\circ\text{C}$		10		
$I_{\text{GSS}}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 30\text{V}$			$\pm 100$	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	3.3	4.2	4.5	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=7\text{A}$		0.29	0.38	$\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{DS}=40\text{V}, I_D=7\text{A}$		20		S
$V_{\text{SD}}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.71	1	V
$I_S$	Maximum Body-Diode Continuous Current				14	A
$I_{\text{SM}}$	Maximum Body-Diode Pulsed Current				56	A
<b>DYNAMIC PARAMETERS</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=25\text{V}, f=1\text{MHz}$	1531	1914	2297	pF
$C_{\text{oss}}$	Output Capacitance		153	191	229	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		11	16	20	pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$	1.75	3.5	5.3	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=400\text{V}, I_D=14\text{A}$		42.8	51	nC
$Q_{gs}$	Gate Source Charge			9.3	11	nC
$Q_{gd}$	Gate Drain Charge			20.3	24	nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=10\text{V}, V_{DS}=250\text{V}, I_D=14\text{A}, R_G=25\Omega$		44	53	ns
$t_r$	Turn-On Rise Time			84	101	ns
$t_{D(\text{off})}$	Turn-Off DelayTime			92	110	ns
$t_f$	Turn-Off Fall Time			50	60	ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=14\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$		289	347	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=14\text{A}, dI/dt=100\text{A}/\mu\text{s}, V_{DS}=100\text{V}$		4.93	6	$\mu\text{C}$

A: The value of  $R_{\text{JA}}$  is measured with the device in a still air environment with  $T_A=25^\circ\text{C}$ .B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=150^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.C. Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=150^\circ\text{C}$ . Ratings are based on low frequency and duty cycles to keep initial  $T_J=25^\circ\text{C}$ .D. The  $R_{\text{JA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{JC}}$  and case to ambient.E. The static characteristics in Figures 1 to 6 are obtained using  $<300\ \mu\text{s}$  pulses, duty cycle 0.5% max.F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=150^\circ\text{C}$ . The SOA curve provides a single pulse rating.G.  $L=60\text{mH}, I_{AS}=6\text{A}, V_{DD}=50\text{V}, R_G=25\Omega$ , Starting  $T_J=25^\circ\text{C}$ 

Rev 2. Dec-08

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.

### TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

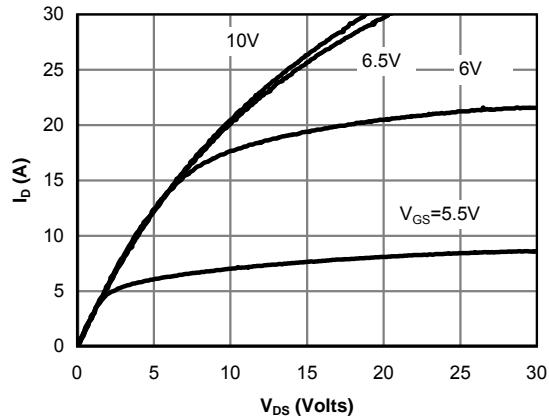


Fig 1: On-Region Characteristics

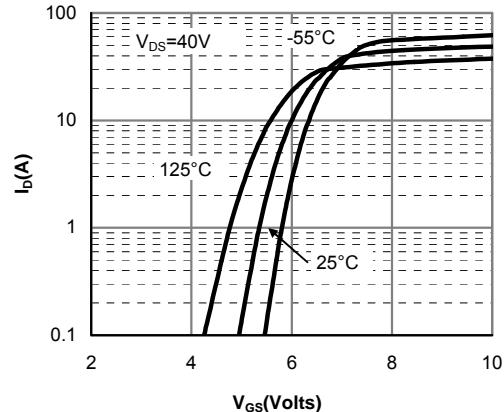


Figure 2: Transfer Characteristics

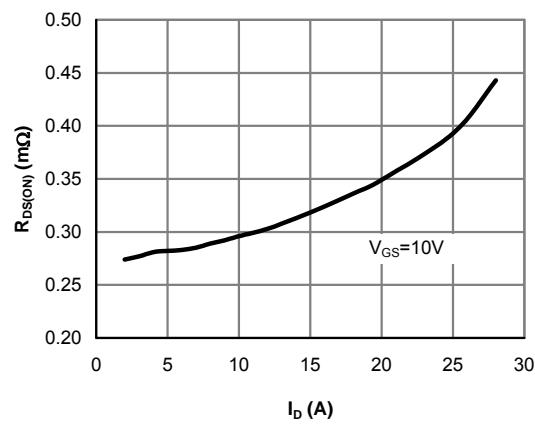


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

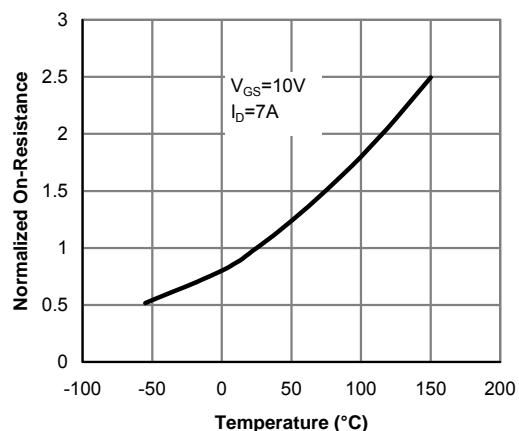


Figure 4: On-Resistance vs. Junction Temperature

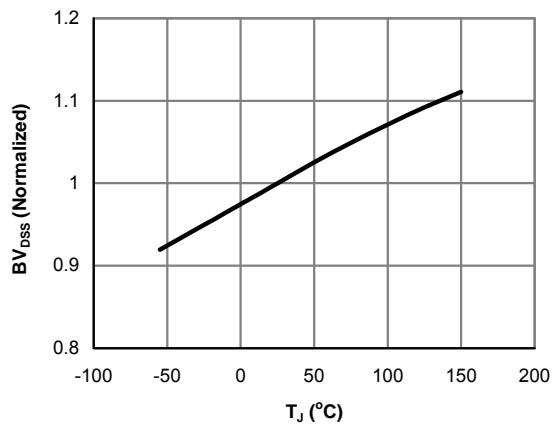


Figure 5: Break Down vs. Junction Temperature

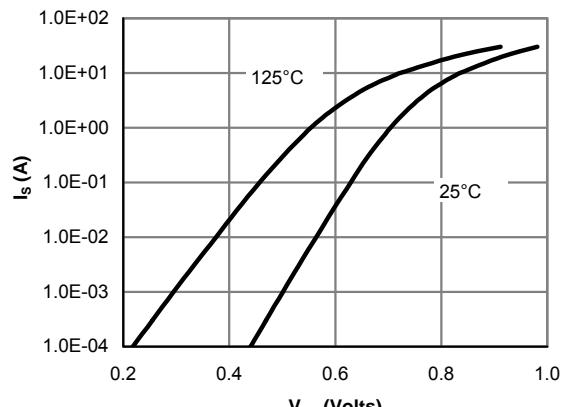


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

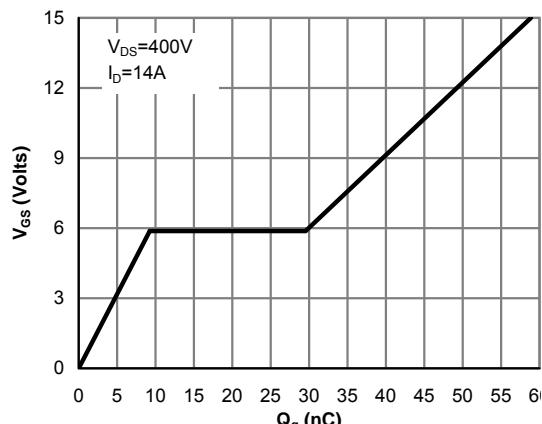


Figure 7: Gate-Charge Characteristics

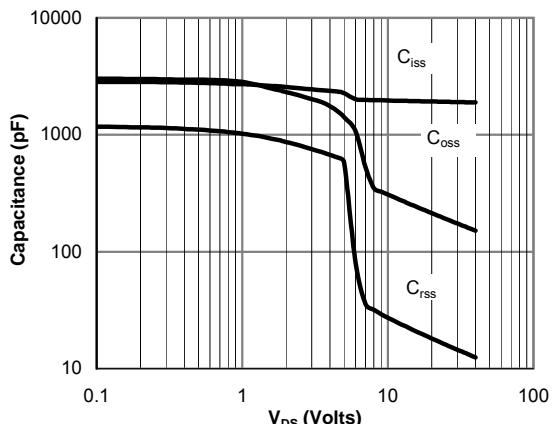


Figure 8: Capacitance Characteristics

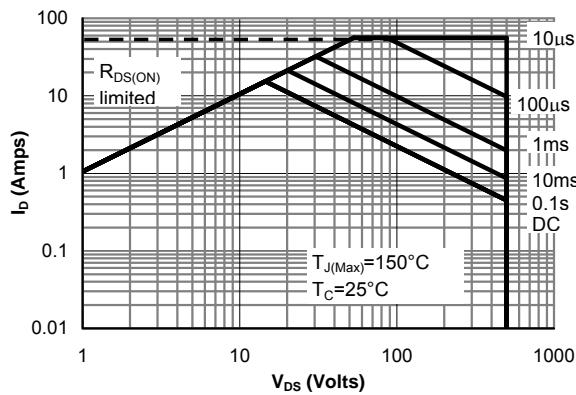


Figure 9: Maximum Forward Biased Safe Operating Area for AOT14N50 (Note F)

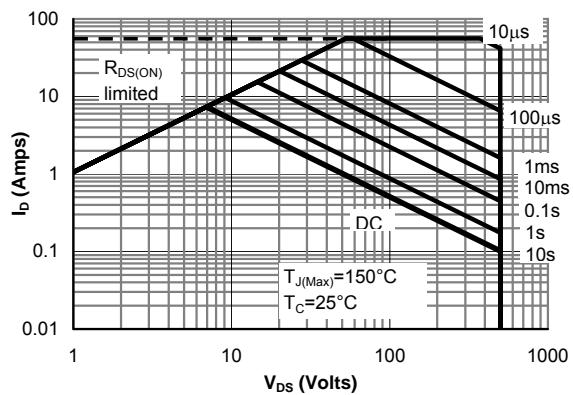


Figure 10: Maximum Forward Biased Safe Operating Area for AOTF14N50 (Note F)

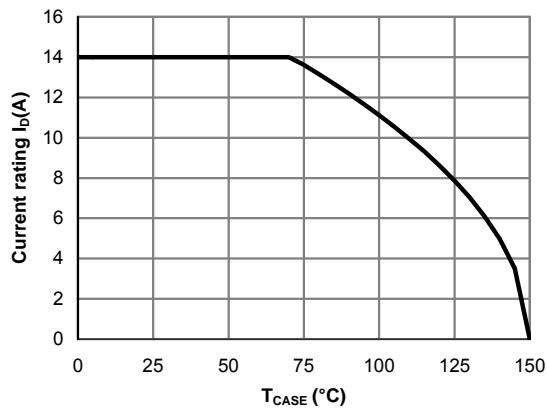


Figure 11: Current De-rating (Note B)

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

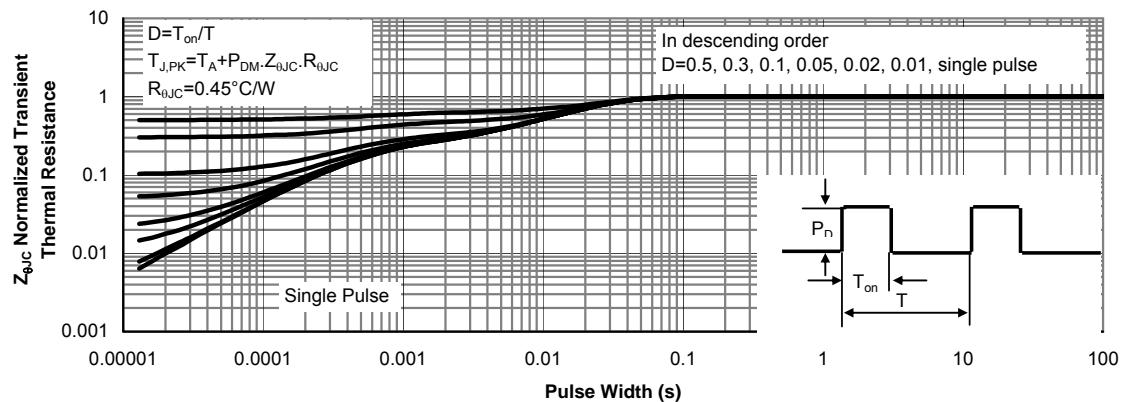


Figure 12: Normalized Maximum Transient Thermal Impedance for AOT14N50 (Note F)

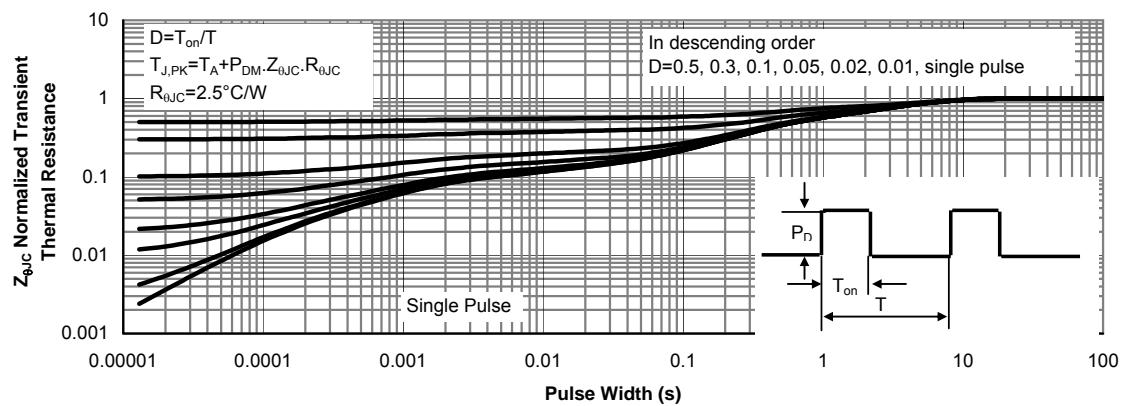
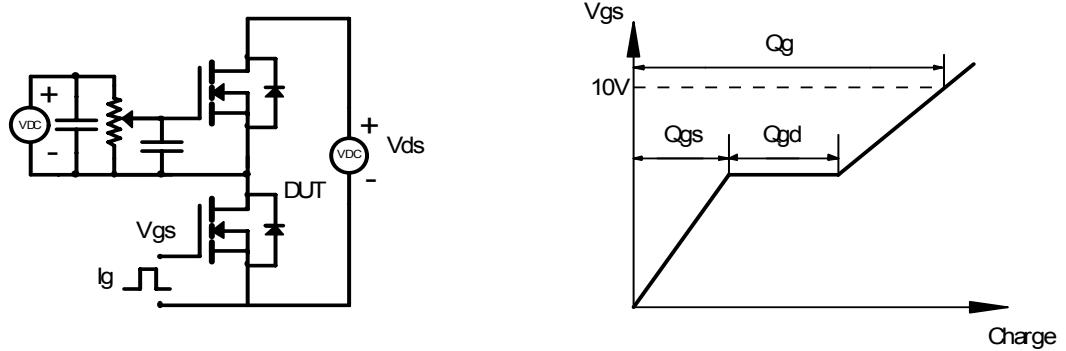
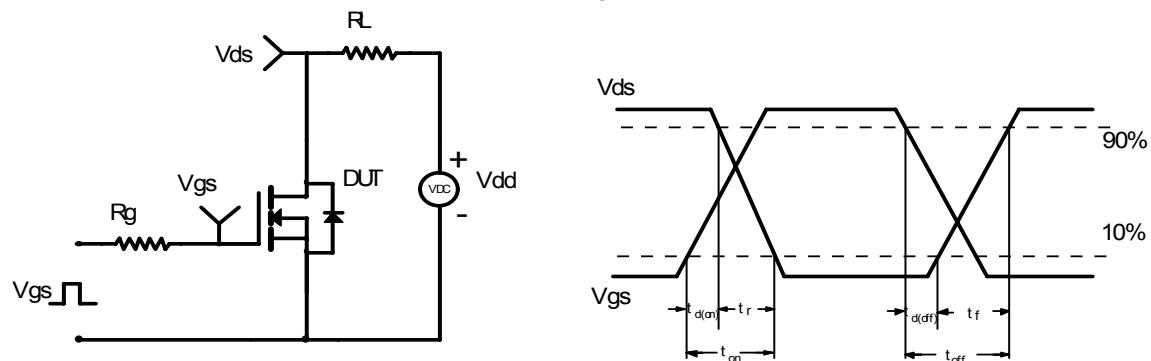


Figure 13: Normalized Maximum Transient Thermal Impedance for AOTF14N50 (Note F)

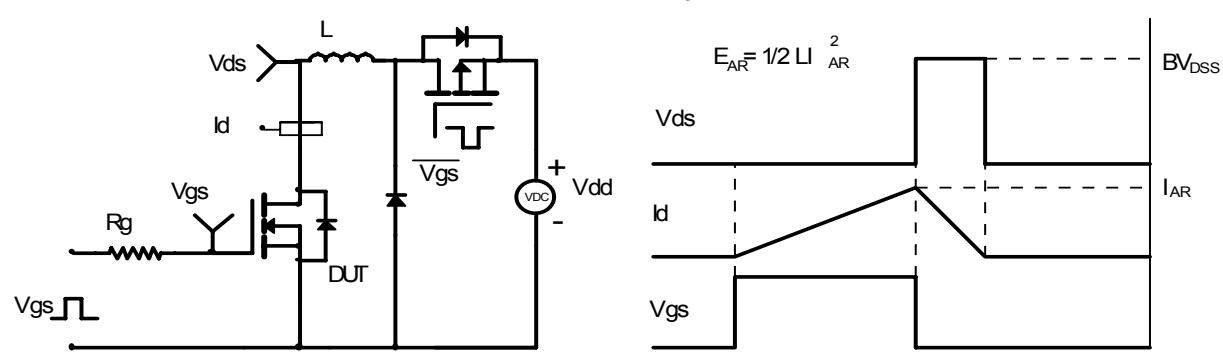
Gate Charge Test Circuit & Waveform



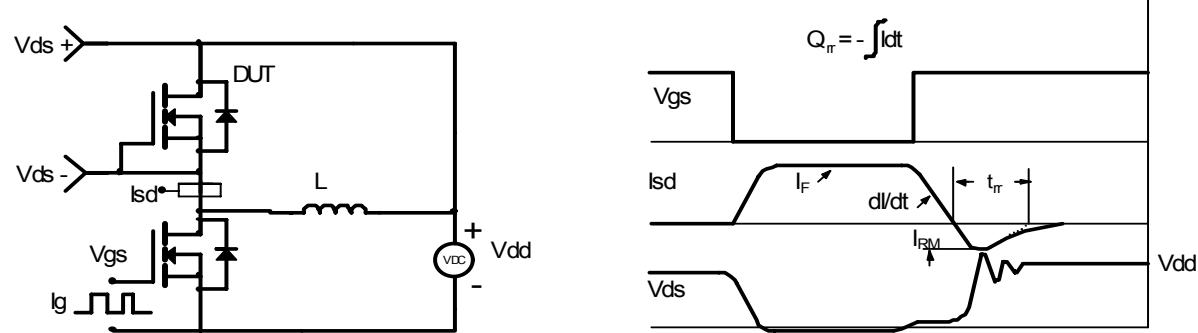
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



# X-ON Electronics

Largest Supplier of Electrical and Electronic Components

***Click to view similar products for MOSFET category:***

***Click to view products by Alpha & Omega manufacturer:***

Other Similar products are found below :

[IRFD120](#) [JANTX2N5237](#) [BUK455-60A/B](#) [MIC4420CM-TR](#) [VN1206L](#) [NDP4060](#) [SI4482DY](#) [IPS70R2K0CEAKMA1](#) [SQD23N06-31L-GE3](#)  
[TK16J60W,S1VQ\(O](#) [2SK2614\(TE16L1,Q\)](#) [DMN1017UCP3-7](#) [DMN1053UCP4-7](#) [SQJ469EP-T1-GE3](#) [NTE2384](#) [DMC2700UDMQ-7](#)  
[DMN2080UCB4-7](#) [DMN61D9UWQ-13](#) [US6M2GTR](#) [DMN31D5UDJ-7](#) [DMP22D4UFO-7B](#) [DMN1006UCA6-7](#) [DMN16M9UCA6-7](#)  
[STF5N65M6](#) [IRF40H233XTMA1](#) [STU5N65M6](#) [DMN6022SSD-13](#) [DMN13M9UCA6-7](#) [DMTH10H4M6SPS-13](#) [DMN2990UFB-7B](#)  
[IPB80P04P405ATMA2](#) [2N7002W-G](#) [MCAC30N06Y-TP](#) [MCQ7328-TP](#) [NTMC083NP10M5L](#) [BXP7N65D](#) [BXP4N65F](#) [AOL1454G](#)  
[WMJ80N60C4](#) [BXP2N20L](#) [BXP2N65D](#) [BXT1150N10J](#) [BXT1700P06M](#) [TSM60NB380CP ROG](#) [RQ7L055BGTCR](#) [DMNH15H110SK3-13](#)  
[SLF10N65ABV2](#) [BSO203SP](#) [BSO211P](#) [IPA60R230P6](#)